Notic of R ferences Cited

| Application/Control No. 10/647,922 | Applicant(s)/Pa Reexamination TANAKA ET Al | |
|------------------------------------|--|-------------|
| Examiner | Art Unit | |
| S. V. Clark | 2815 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|---|
| | A | US-5,409,865 | 04-1995 | Karnezos, Marcos | 29/827 |
| | В | US-6,509,643 | 01-2003 | Ohtaka et al. | 257/712 |
| | С | US-5,420,460 | 05-1995 | Massingill, Thomas J. | 257/693 |
| | D | US-5,844,168 | 12-1998 | Schueller et al. | 174/52.4 |
| | E | US-6,259,154 | 07-2001 | Niwa, Koichiro | 257/678 |
| | F | US-6,436,733 | 08-2002 | Yukawa, Masahiko | 438/118 |
| | G | US-6,621,160 | 09-2003 | Shibamoto et al. | 257/712 |
| | Н | US-6,696,764 | 02-2004 | Honda, Hirokazu | 257/778 |
| | | US-6,734,535 | 05-2004 | Hashimoto, Nobuaki | 257/668 |
| | J | US- | | | , |
| | K | US- | | | |
| | L | US- | | | · |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|-----------------|---------|------|----------------|
| | N | 2002-124549 | 04-2002 | Japan | | |
| | 0 | 2002-16175 | 01-2002 | Japan | | |
| | Р | 2001-110936 | 04-2001 | Japan | | |
| | Q | 2002-118217 | 04-2002 | Japan | | |
| | R | | | - | | |
| | s | | | | | , |
| | Т | | | | | 1 |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | | |
| , | U | |
| | ٧ | |
| | w | |
| | х | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.